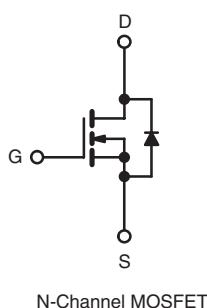
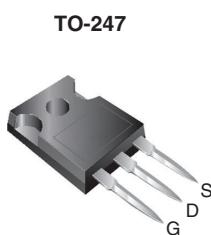


Power MOSFET

PRODUCT SUMMARY		
V_{DS} (V)	60	
$R_{DS(on)}$ (Ω)	$V_{GS} = 10$ V	0.014
Q_g (Max.) (nC)	160	
Q_{gs} (nC)	48	
Q_{gd} (nC)	54	
Configuration	Single	



ORDERING INFORMATION

Package	TO-247
Lead (Pb)-free	IRFP054PbF SiHFP054-E3
SnPb	IRFP054 SiHFP054

ABSOLUTE MAXIMUM RATINGS $T_C = 25$ °C, unless otherwise noted

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V_{DS}	60	V
Gate-Source Voltage	V_{GS}	± 20	
Continuous Drain Current ^e	I_D	70	A
Continuous Drain Current		64	
Pulsed Drain Current ^a	I_{DM}	360	
Linear Derating Factor		1.5	W/°C
Single Pulse Avalanche Energy ^b	E_{AS}	640	mJ
Maximum Power Dissipation	P_D	230	W
Peak Diode Recovery dV/dt ^c	dV/dt	4.5	V/ns
Operating Junction and Storage Temperature Range	T_J, T_{stg}	- 55 to + 175	°C
Soldering Recommendations (Peak Temperature) ^d	for 10 s	300	
Mounting Torque		10	lbf · in
		1.1	N · m

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. $V_{DD} = 25$ V, starting $T_J = 25$ °C, $L = 92 \mu\text{H}$, $R_G = 25 \Omega$, $I_{AS} = 90$ A (see fig. 12).
- c. $I_{SD} \leq 90$ A, $dI/dt \leq 200$ A/ μ s, $V_{DD} \leq V_{DS}$, $T_J \leq 175$ °C.
- d. 1.6 mm from case.
- e. Current limited by the package, (die current = 90 A).

* Pb containing terminations are not RoHS compliant, exemptions may apply



RoHS*
COMPLIANT

FEATURES

- Dynamic dV/dt Rating
- Isolated Central Mounting Hole
- 175 °C Operating Temperature
- Fast Switching
- Ease of Parallelizing
- Simple Drive Requirements
- Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-247 package is preferred for commercial-industrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because of its isolated mounting hole. It also provides greater creepage distance between pins to meet the requirements of most safety specifications.

THERMAL RESISTANCE RATINGS

PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	40	°C/W
Case-to-Sink, Flat, Greased Surface	R_{thCS}	0.24	-	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	0.65	

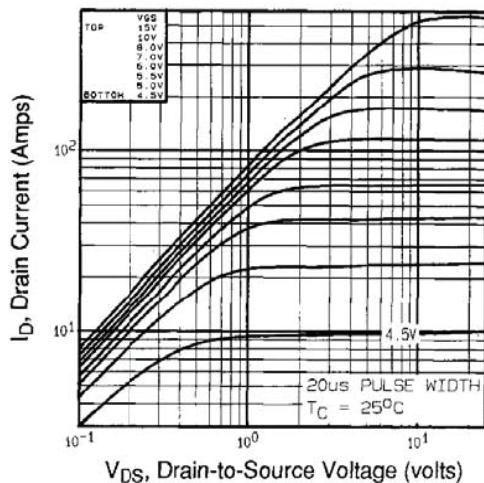
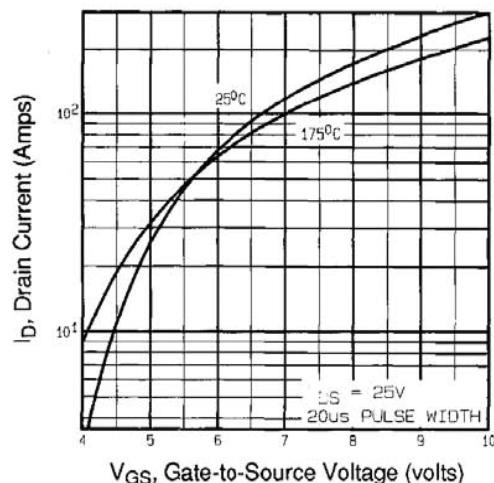
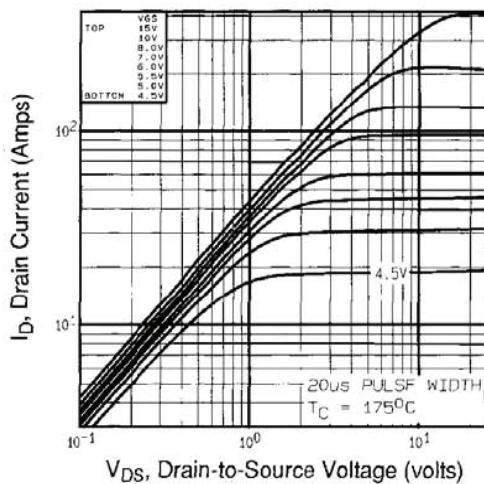
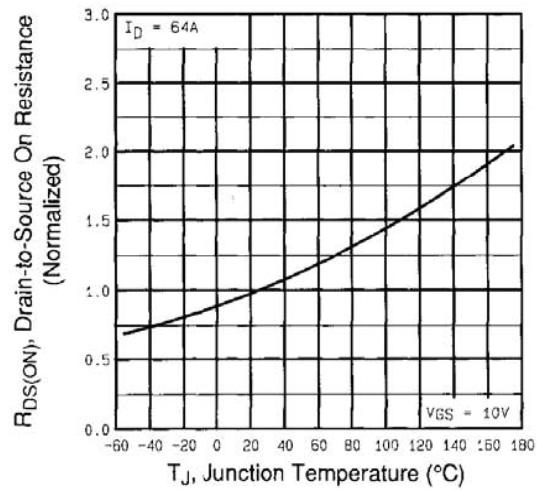
SPECIFICATIONS $T_J = 25^\circ\text{C}$, unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static								
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}$	$I_D = 250 \mu\text{A}$	60	-	-	V	
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to 25°C , $I_D = 1 \text{ mA}$		-	0.056	-	$^\circ\text{C}/\text{C}$	
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$		2.0	-	4.0	V	
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 60 \text{ V}$, $V_{GS} = 0 \text{ V}$		-	-	25	μA	
		$V_{DS} = 48 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_J = 150^\circ\text{C}$		-	-	250		
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$	$I_D = 54 \text{ A}^b$	-	-	0.014	Ω	
Forward Transconductance	g_{fs}	$V_{DS} = 25 \text{ V}$, $I_D = 54 \text{ A}^b$		25	-	-	S	
Dynamic								
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, $f = 1.0 \text{ MHz}$, see fig. 5		-	4500	-	pF	
Output Capacitance	C_{oss}			-	2000	-		
Reverse Transfer Capacitance	C_{rss}			-	300	-		
Total Gate Charge	Q_g	$V_{GS} = 10 \text{ V}$	$I_D = 64 \text{ A}$, $V_{DS} = 48 \text{ V}$, see fig. 6 and 13 ^b	-	-	160	nC	
Gate-Source Charge	Q_{gs}			-	-	48		
Gate-Drain Charge	Q_{gd}			-	-	54		
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 30 \text{ V}$, $I_D = 64 \text{ A}$, $R_G = 6.2 \Omega$, $R_D = 0.45 \Omega$, see fig. 10 ^b		-	20	-	ns	
Rise Time	t_r			-	160	-		
Turn-Off Delay Time	$t_{d(off)}$			-	83	-		
Fall Time	t_f			-	150	-		
Internal Drain Inductance	L_D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	nH	
Internal Source Inductance	L_S			-	13	-		
Drain-Source Body Diode Characteristics								
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	70	A	
Pulsed Diode Forward Current ^a	I_{SM}			-	-	360		
Body Diode Voltage	V_{SD}	$T_J = 25^\circ\text{C}$, $I_S = 90 \text{ A}$, $V_{GS} = 0 \text{ V}^b$		-	-	2.5	V	
Body Diode Reverse Recovery Time	t_{rr}	$T_J = 25^\circ\text{C}$, $I_F = 6.4 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}^b$		-	270	540	ns	
Body Diode Reverse Recovery Charge	Q_{rr}			-	1.1	2.2	μC	
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)						

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width $\leq 300 \mu\text{s}$; duty cycle $\leq 2\%$.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Fig. 1 - Typical Output Characteristics, $T_c = 25\text{ }^\circ\text{C}$

Fig. 3 - Typical Transfer Characteristics

Fig. 2 - Typical Output Characteristics, $T_c = 175\text{ }^\circ\text{C}$

Fig. 4 - Normalized On-Resistance vs. Temperature

IRFP054, SiHFP054

Vishay Siliconix

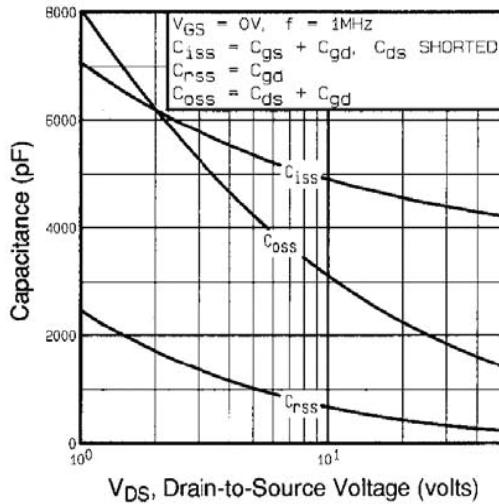


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

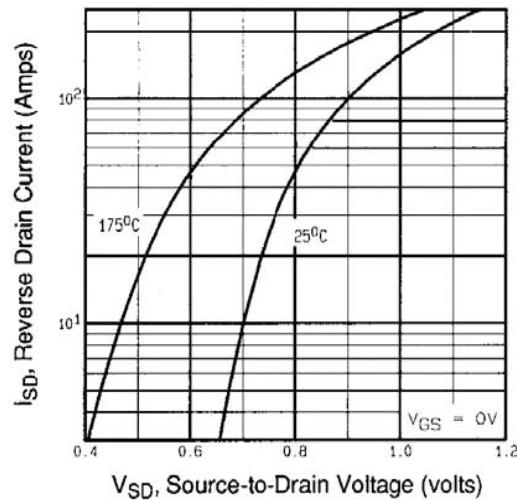


Fig. 7 - Typical Source-Drain Diode Forward Voltage

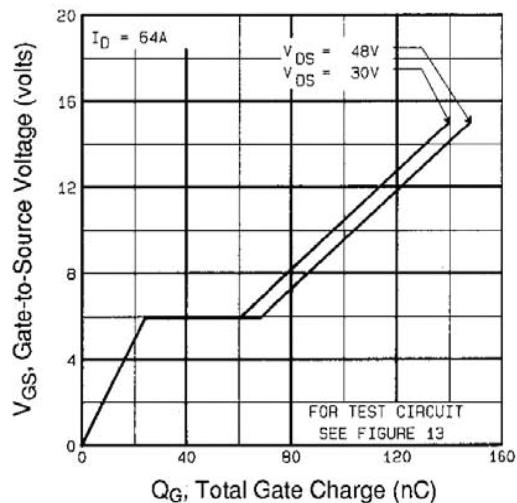


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

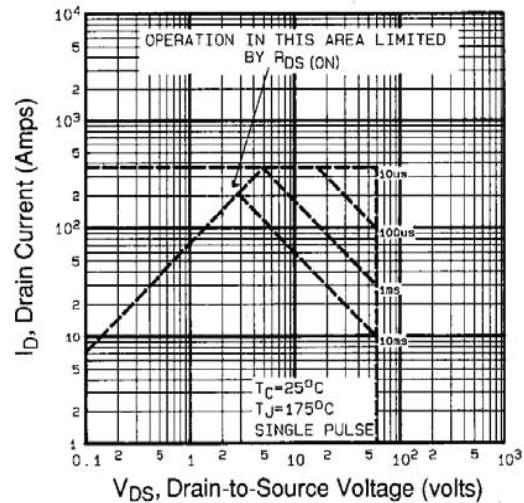


Fig. 8 - Maximum Safe Operating Area

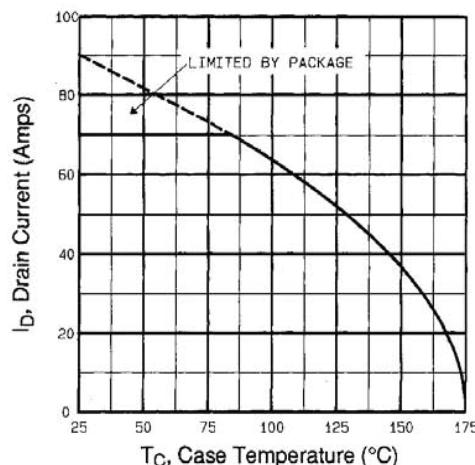


Fig. 9 - Maximum Drain Current vs. Case Temperature

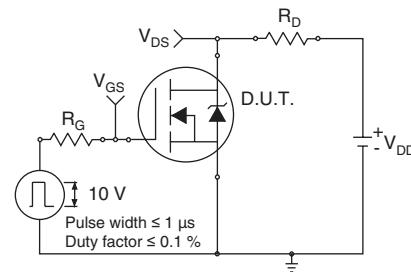


Fig. 10a - Switching Time Test Circuit

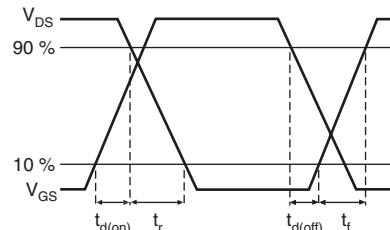


Fig. 10b - Switching Time Waveforms

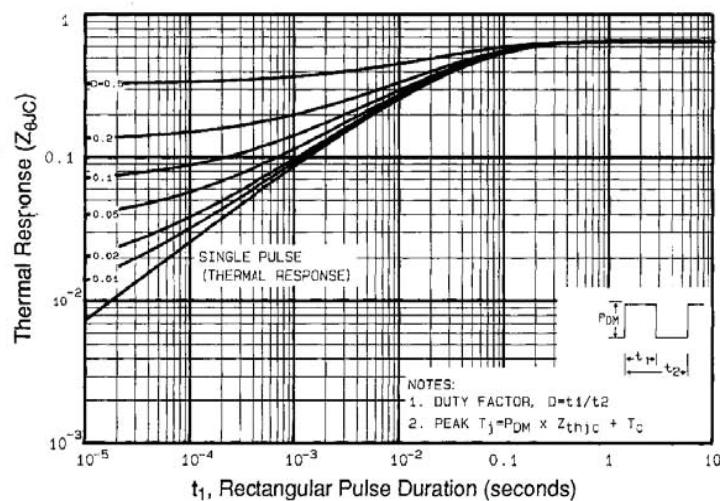


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

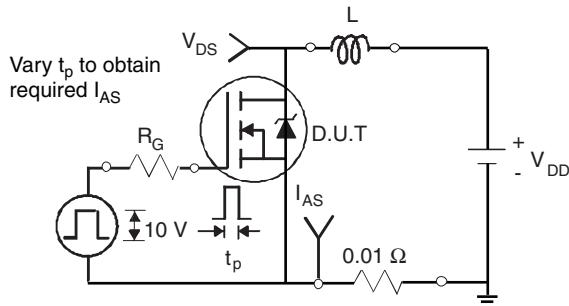


Fig. 12a - Unclamped Inductive Test Circuit

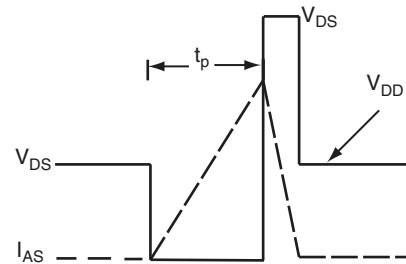


Fig. 12b - Unclamped Inductive Waveforms

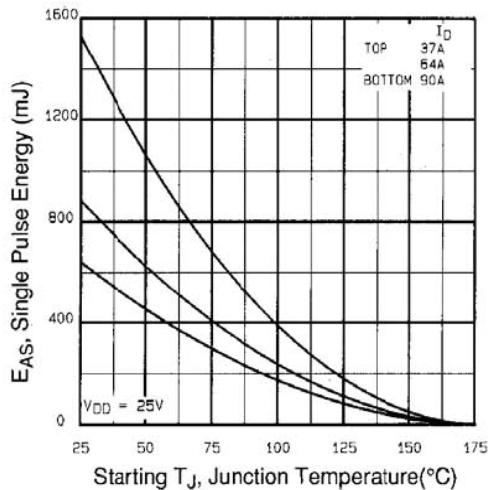


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

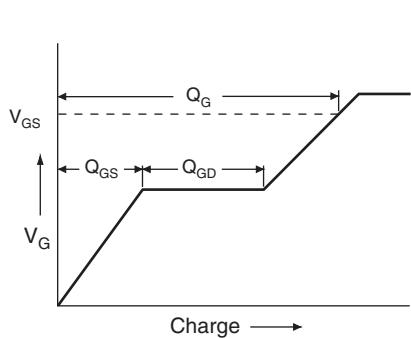


Fig. 13a - Basic Gate Charge Waveform

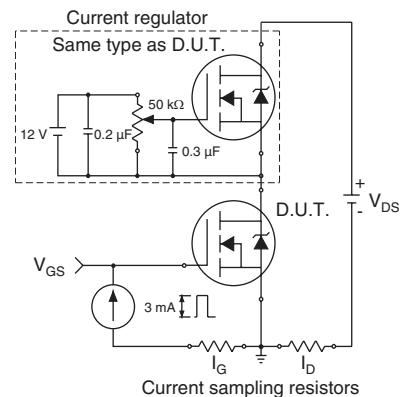
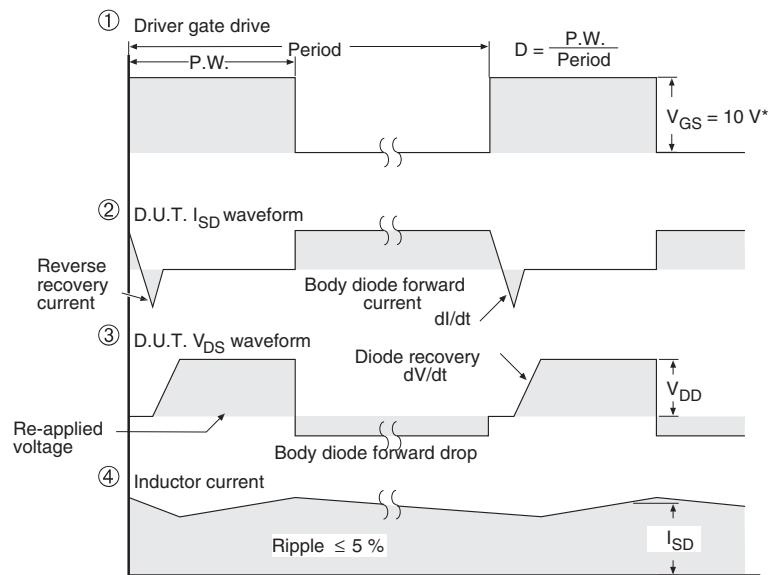
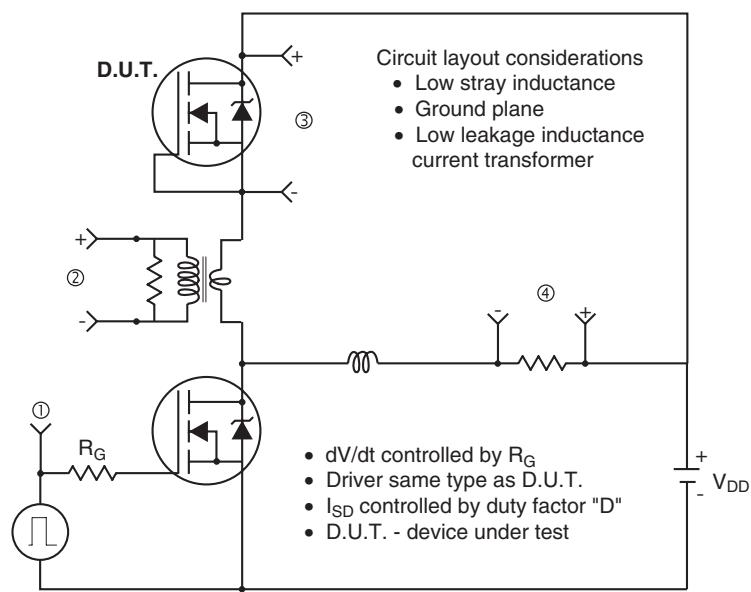


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit



* $V_{GS} = 5 \text{ V}$ for logic level devices

Fig. 14 - For N-Channel

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